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AMENDMENT TO THE SPECIFICATION

The following amendment corrects a clerical error to change the date cited in the Drennan et al. article from "2000" to --1999--. (Please note that any other underlined text is not used to mark added material but rather is part of the existing text to connote the article titles.) Please replace the first paragraph of the "Detailed Description of the Drawings" section with the following amended paragraph:

--Referring to FIG. 1, a simplified functional block diagram of a mismatch modeling tool 10 in an embodiment in accordance with the present invention is shown (the "mismatch tool 10" hereinafter). The mismatch tool 10 comprises the mismatch model  $\sigma_{id}^2 = \Sigma (\partial I_d / \partial p_j)^2 \sigma_{pj}^2$  ("mismatch model 30" hereinafter). The derivation and explanation of the mismatch model 30 is contained within the paper A Comprehensive MOSFET Mismatch Model by P. Drennan and C. McAndrew, IEEE ICMTS, [2000] 1999 ("Drennan et al." hereinafter), the contents of which are incorporated herein by reference. Further explanation of the model is contained within Integrated Circuit Device Mismatch Modeling and Characterization for Analog Circuit Design, - Ph.D. dissertation, Arizona State University, May 1999, by P. Drennan ("Drennan" hereinafter) which is also incorporated herein by reference.--